

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10717741	CONROY ET AL.
Examiner		Art Unit
Keefer, Michael E		2454

SEARCHED

Class	Subclass	Date	Examiner
709	206 (updated 6/20/2009)	6/28/2007	MEK

SEARCH NOTES

Search Notes	Date	Examiner
EAST Search	6/28/2007	MEK
Google Search	6/28/2007	MEK
ACM Search	6/29/2007	MEK
IEEE Xplore Search	6/29/2007	MEK
EAST Search	9/13/2008	MEK
Consulted Primary Examiner Dustin Nguyen, Class 709	2/26/2009	MEK
Consulted Examiner Hassan Phillips, Class 709	2/26/2009	MEK
EAST Search	6/20/2009	MEK

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner